

Notice of References Cited	Application/Control No. 10/782,654	Applicant(s)/Patent Under Reexamination SAITO ET AL.	
	Examiner David L. Ometz	Art Unit 2653	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,790,541	09-2004	Saito et al.	428/692
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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Notice of References Cited	Application/Control No. 09/834,105	Applicant(s)/Patent Under Reexamination SAITO ET AL.	
	Examiner Louis Falasco	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,993,956	11-1999	Lambeth et al.	428/900
	B	US-6,132,892	10-2000	Yoshikawa et al.	428/692
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	J	US-			
	K	US-			
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